On the crystallization of Ta$_2$O$_5$ nanotubes:

Structural and local atomic properties

investigated by EXAFS and XRD

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Supplementary Figures

Figure S1. XRD diffractograms of the Ta₂O₅ NTs annealed at 800 °C for 60, 120, 300 and 600 min.
Figure S2. TEM images: A and B are amorphous Ta$_2$O$_5$ NTs and C and D are NTs annealed at 800 °C for 30 min.
Figure S3. (a, b) $k^3$-weighted Ta L₃ EXAFS signal and (c, d) the corresponding Fourier transform magnitude. Red lines represent the best fits obtained.